MSKSEMI















ESD

TVS

TSS

MOV

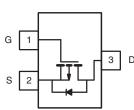
GDT

PLED

Broduct data sheet







Features

- -20V,-2.0A, RDS(ON) =85mΩ@VGS =-4.5V
- Improved dv/dt capability
- Fast switching
- Green Device Available

Applications

- Notebook
- Load Switch
- Hand-Held Instruments

BVDSS	RDSON	ID
-20V	85m Ω	-2.0A

Absolute Maximum Ratings Tc=25°C unless otherwise noted

Symbol	Parameter	Rating	Units
V _{DS}	Drain-Source Voltage	-20	V
V _{GS}	Gate-Source Voltage	±12	V
	Drain Current – Continuous (T _C =25°C)	-2.0	Α
I _D	Drain Current – Continuous (T _C =100°C)	-1.6	А
I _{DM}	Drain Current – Pulsed ¹	-5.0	Α
D	Power Dissipation (T _C =25°C)	1.56	W
P_D	Power Dissipation – Derate above 25°C	0.012	W/°C
T _{STG}	Storage Temperature Range	-55 to 150	°C
T _J	Operating Junction Temperature Range	-55 to 150	°C

Thermal Characteristics

Symbol	Parameter	Тур.	Max.	Unit
$R_{\theta JA}$	Thermal Resistance Junction to ambient		80	°C/W



Electrical Characteristics (T_J=25 °C, unless otherwise noted)

Off Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =-250uA	-20			V
$\triangle BV_{DSS}/\triangle T_{J}$	BV _{DSS} Temperature Coefficient	Reference to 25°C , I _D =-1mA		-0.01		V/°C
	Drain Source Leakage Current	V _{DS} =-20V , V _{GS} =0V , T _J =25°C			-1	uA
I _{DSS}	Drain-Source Leakage Current	V _{DS} =-16V , V _{GS} =0V , T _J =125°C			-10	uA
I _{GSS}	Gate-Source Leakage Current	V _{GS} =±12V , V _{DS} =0V			±100	nA

On Characteristics

P		V _{GS} =-4.5V , I _D =-2.0A		85	110	mΩ
$R_{DS(ON)}$	Static Drain-Source On-Resistance	V _{GS} =-2.5V , I _D =-1A		110	150	11122
V _{GS(th)}	Gate Threshold Voltage	\/ -\/ - 250\	-0.3	-0.8	-1.3	V
$\triangle V_{GS(th)}$	V _{GS(th)} Temperature Coefficient	$V_{GS}=V_{DS}$, $I_D=-250uA$		3		mV/°C

Dynamic and switching Characteristics

•					
Q_g	Total Gate Charge ^{2, 3}			3.0	
Q_{gs}	Gate-Source Charge ^{2, 3}	V _{DS} =-10V , V _{GS} =-4.5V , I _D =-1A		0.5	 nC
Q_{gd}	Gate-Drain Charge ^{2, 3}			0.8	
T _{d(on)}	Turn-On Delay Time ^{2, 3}			10	
Tr	Rise Time ^{2 , 3}	Time ^{2, 3} V_{DD} =-10V , V_{GS} =-4.5V , R_{G} =3 Ω		5.5	 20
T _{d(off)}	Turn-Off Delay Time ^{2, 3}	I _D =-1A		20	 nS
T _f	Fall Time ^{2, 3}			6.5	
C _{iss}	Input Capacitance			180	
C _{oss}	Output Capacitance	V _{DS} =-10V , V _{GS} =0V , F=1MHz		35	 pF
C _{rss}	Reverse Transfer Capacitance			25	

Drain-Source Diode Characteristics and Maximum Ratings

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Is	Continuous Source Current	V =V =0V Force Current			-2.0	Α
I _{SM}	Pulsed Source Current	V _G =V _D =0V , Force Current			-4.0	Α
V _{SD}	Diode Forward Voltage	V _{GS} =0V , I _S =-1A , T _J =25°C			-1.2	V

Note:

- 1. Repetitive Rating : Pulsed width limited by maximum junction temperature.
- 2. The data tested by pulsed , pulse width \leq 300us , duty cycle \leq 2%.
- 3. Essentially independent of operating temperature.





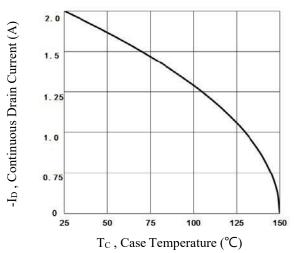


Fig.1 Continuous Drain Current vs. Tc

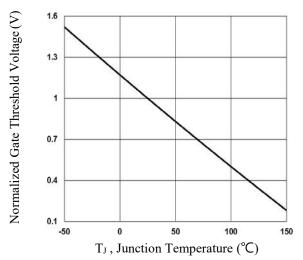
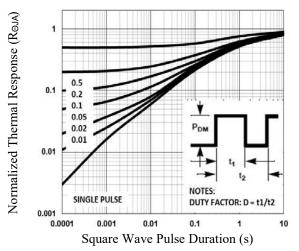
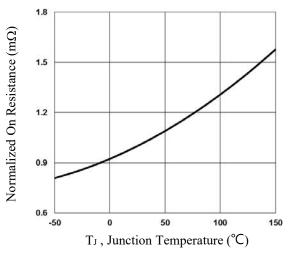


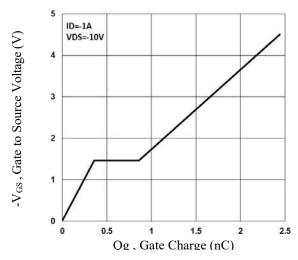
Fig.3 Normalized V_{th} vs. T_J



Normalized Transient Impedance



Normalized RDSON vs. T_J Fig.2



Gate Charge Waveform

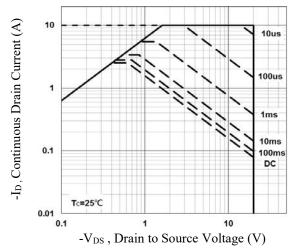
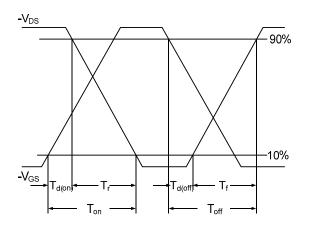


Fig.6 Maximum Safe Operation Area





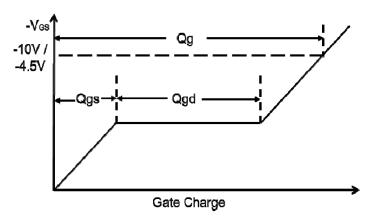
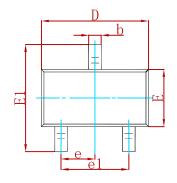


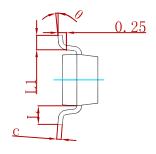
Fig.7 Switching Time Waveform

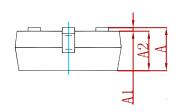
Fig.8 Gate Charge Waveform



PACKAGE MECHANICAL DATA

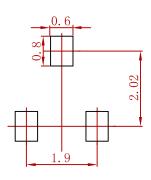






Symbol	Dimensions	Dimensions In Millimeters		s In Inches
Зупівої	Min	Max	Min	Max
Α	0.900	1.150	0.035	0.045
A1	0.000	0.100	0.000	0.004
A2	0.900	1.050	0.035	0.041
b	0.300	0.500	0.012	0.020
С	0.080	0.150	0.003	0.006
D	2.800	3.000	0.110	0.118
E	1.200	1.400	0.047	0.055
E1	2.250	2.550	0.089	0.100
е	0.950 TYP		0.037	7 TYP
e1	1.800	2.000	0.071	0.079
Ĺ	0.550	REF	0.022 REF	
L1	0.300	0.500	0.012	0.020
θ	0°	8°	0°	8°

Suggested Pad Layout



- 1.Controlling dimension:in millimeters.2.General tolerance:± 0.05mm.3.The pad layout is for reference purposes only.

REEL SPECIFICATION

P/N	PKG	QTY
FDN338P	SOT-23	3000



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